

PROBING SOLUTIONS INC.

Probing System Configuration Worksheet

Fill in the blanks below and we will configure a system to meet your needs.

1. Application.

Process Control _____ Failure Analysis _____ Mask Inspection _____
Test Support _____ Device Characterization _____ Other _____

2. Tell us about what you are probing.

Wafer Size _____ Packaged Parts _____ Die Size _____
MW Substrate _____ Smallest Line Width _____ Pad Size _____

3. What do you want for a "base" probe station:

Chuck size: 4-inch, 6-inch, 8-inch (specify) _____
Chuck type: Gold-ambient _____ Stainless Steel _____ Hot/Cold Chuck _____
Low Noise (Triaxial) _____ Hot Chuck (only) _____
Stage drive control desired:
Manual _____ Motorized _____ Semiautomatic _____
Programmable: your host _____ Metrics _____ LabView _____
Internal RS-232 _____ GPIB _____ Mosaid _____

4. Microscope options:

Type: Stereo Zoom, A-Zoom, USMCO (specify) _____
Objectives: 2x, 10x, 20x _____ 2.25x, 8x, 25x _____ Other _____
Special _____x UV _____ IR _____
Drive: Manual standard (5-10 micron resolution) _____ Range 1" x 1" _____
Manual High Resolution (0.6 micron) _____ (X & Y) 2" x 2" _____
Motorized _____ 4" x 4" _____

5. Manipulators needed:

Manual: 50 TPI _____ 100 TPI _____ 200 TPI _____
Type: Mini-arc _____ Rectilinear _____ Qty _____
Target size to probe _____

6. Probes:

Current Level Low _____ High _____ RF/Microwave _____
Frequency Range Low _____ High _____

7. Key Options:

Laser Cutter _____ Anti-vibration table _____ MW Frequency: _____
Probe card holder _____ Light-tight Enclosure _____ DC to 1.3 GHz _____
(4.5" w/standard) _____ Vib Table Integration _____ DC to 20 GHz _____
Touchdown sense _____ Video system _____ DC to 40 GHz _____
(probe card based) _____ HC to _____

8. Will you be interfacing your prober, through software, to a test instrument? Please list the instruments and your test equipment configuration (use the back of this form).